

<b>Notice of References Cited</b>	Application/Control No. 10/531,371		Applicant(s)/Patent Under Reexamination GRUNDL ET AL.	
	Examiner Jeffrey J. Restifo		Art Unit 3618	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,670,838 A	09-1997	Everton, John M.	310/254
*	B	US-5,678,646 A	10-1997	Fliege, Hans	180/65.1
*	C	US-5,731,643 A	03-1998	Avakian et al.	310/53
*	D	US-5,833,022 A	11-1998	Welke, Knut	180/65.2
*	E	US-5,904,631 A	05-1999	Morisawa et al.	475/5
*	F	US-5,973,460 A	10-1999	Taga et al.	318/139
*	G	US-2001/0024997 A1	09-2001	Sugano et al.	477/2
*	H	US-6,520,879 B2	02-2003	Kawabata et al.	475/5
*	I	US-6,527,659 B1	03-2003	Klemen et al.	475/5
*	J	US-2003/0102174 A1	06-2003	Bordini, Giorgio	180/65.2
*	K	US-6,579,202 B2	06-2003	El-Antably et al.	475/159
*	L	US-2003/0173840 A1	09-2003	Seniawski et al.	310/54
*	M	US-6,661,109 B2	12-2003	Fukasaku et al.	290/40C

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/531,371		Applicant(s)/Patent Under Reexamination GRUNDL ET AL.	
	Examiner Jeffrey J. Restifo		Art Unit 3618	Page 2 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0226653 A1	12-2003	Takedomi et al.	165/43
*	B	US-2004/0124722 A1	07-2004	Uchida et al.	310/054
*	C	US-2004/0154846 A1	08-2004	Kira, Nobuhiro	180/065.6
*	D	US-2004/0226761 A1	11-2004	Takenaka et al.	180/065.1
*	E	US-6,945,894 B2	09-2005	Holmes, Alan G.	475/5
*	F	US-RE38,790 E	09-2005	Maeda et al.	290/40C
*	G	US-7,002,267 B2	02-2006	Raszkowski et al.	310/54
*	H	US-2006/0027192 A1	02-2006	Tsukada et al.	123/041.7
*	I	US-RE39,205 E	07-2006	Sasaki, Shoichi	318/150
*	J	US-7,174,978 B2	02-2007	Taniguchi et al.	180/65.1
*	K	US-7,211,913 B2	05-2007	Tsutsui et al.	310/54
*	L	US-7,239,033 B2	07-2007	Motoike et al.	290/40C
*	M	US-7,284,313 B2	10-2007	Raszkowski et al.	29/596

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/531,371		Applicant(s)/Patent Under Reexamination GRUNDL ET AL.	
	Examiner Jeffrey J. Restifo		Art Unit 3618	Page 3 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2008/0103003 A1	05-2008	SAH et al.	475/5
*	B	US-7,393,296 B2	07-2008	Kano et al.	475/5
*	C	US-2008/0184706 A1	08-2008	Uno et al.	60/667
*	D	US-7,426,971 B2	09-2008	Kano et al.	180/65.2
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.